

General Description

The GreenMOS® high voltage MOSFET utilizes charge balance technology to achieve outstanding low on-resistance and lower gate charge. It is engineered to minimize conduction loss, provide superior switching performance and robust avalanche capability.

The GreenMOS® Z series is integrated with fast recovery diode (FRD) to minimize reverse recovery time. It is suitable for resonant switching topologies to reach higher efficiency, higher reliability and smaller form factor.

Features

- Low $R_{DS(ON)}$ & FOM
- Extremely low switching loss
- Excellent stability and uniformity
- Ultra-fast and robust body diode

Applications

- PC power
- Telecom power
- Server power
- EV Charger
- Motor driver



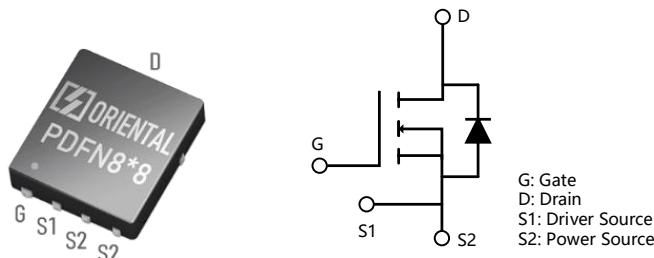
Key Performance Parameters

Parameter	Value	Unit
V_{DS} , min @ $T_{j(max)}$	650	V
I_D , pulse	90	A
$R_{DS(ON)}$, max @ $V_{GS}=10V$	108	mΩ
Q_g	37.1	nC

Marking Information

Product Name	Package	Marking
OSG60R108JZF	PDFN8*8	OSG60R108JZ

Package & Pin Information



Absolute Maximum Ratings at $T_j=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Value	Unit
Drain-source voltage	V_{DS}	600	V
Gate-source voltage	V_{GS}	± 30	V
Continuous drain current ¹⁾ , $T_C=25^\circ\text{C}$	I_D	30	A
Continuous drain current ¹⁾ , $T_C=100^\circ\text{C}$		19	
Pulsed drain current ²⁾ , $T_C=25^\circ\text{C}$	$I_{D, \text{pulse}}$	90	A
Continuous diode forward current ¹⁾ , $T_C=25^\circ\text{C}$	I_S	30	A
Diode pulsed current ²⁾ , $T_C=25^\circ\text{C}$	$I_{S, \text{pulse}}$	90	A
Power dissipation ³⁾ , $T_C=25^\circ\text{C}$	P_D	101	W
Single pulsed avalanche energy ⁵⁾	E_{AS}	1000	mJ
MOSFET dv/dt ruggedness, $V_{DS}=0\dots 480\text{ V}$	dv/dt	50	V/ns
Reverse diode dv/dt, $V_{DS}=0\dots 480\text{ V}$, $I_{SD} \leq I_D$	dv/dt	50	V/ns
Operation and storage temperature	T_{stg}, T_j	-55 to 150	°C

Thermal Characteristics

Parameter	Symbol	Value	Unit
Thermal resistance, junction-case	$R_{\theta JC}$	1.24	°C/W
Thermal resistance, junction-ambient ⁴⁾	$R_{\theta JA}$	62	°C/W

Electrical Characteristics at $T_j=25^\circ\text{C}$ unless otherwise specified

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Drain-source breakdown voltage	BV_{DSS}	600			V	$V_{GS}=0\text{ V}$, $I_D=1\text{ mA}$
		650				$V_{GS}=0\text{ V}$, $I_D=1\text{ mA}$, $T_j=150^\circ\text{C}$
Gate threshold voltage	$V_{GS(\text{th})}$	3		4.5	V	$V_{DS}=V_{GS}$, $I_D=1\text{ mA}$
Drain-source on-state resistance	$R_{DS(\text{ON})}$		0.085	0.108	Ω	$V_{GS}=10\text{ V}$, $I_D=15\text{ A}$
			0.2			$V_{GS}=10\text{ V}$, $I_D=15\text{ A}$, $T_j=150^\circ\text{C}$
Gate-source leakage current	I_{GSS}			100	nA	$V_{GS}=30\text{ V}$
				-100		$V_{GS}=-30\text{ V}$
Drain-source leakage current	I_{DSS}			10	μA	$V_{DS}=600\text{ V}$, $V_{GS}=0\text{ V}$

Dynamic Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Input capacitance	C _{iss}		2674.5		pF	V _{GS} =0 V, V _{DS} =50 V, f=100 KHz
Output capacitance	C _{oss}		246.0		pF	
Reverse transfer capacitance	C _{rss}		9.6		pF	
Turn-on delay time	t _{d(on)}		67.4		ns	V _{GS} =10 V, V _{DS} =400 V, R _G =2 Ω, I _D =16 A
Rise time	t _r		71.1		ns	
Turn-off delay time	t _{d(off)}		103.9		ns	
Fall time	t _f		33.4		ns	

Gate Charge Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Total gate charge	Q _g		37.1		nC	V _{GS} =10 V, V _{DS} =400 V, I _D =16 A
Gate-source charge	Q _{gs}		11.0		nC	
Gate-drain charge	Q _{gd}		13.8		nC	
Gate plateau voltage	V _{plateau}		6.7		V	

Body Diode Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Diode forward voltage	V _{SD}			1.4	V	I _S =30 A, V _{GS} =0 V
Reverse recovery time	t _{rr}		123.0		ns	
Reverse recovery charge	Q _{rr}		0.73		uC	
Peak reverse recovery current	I _{rrm}		11.0		A	

Note

- 1) Calculated continuous current based on maximum allowable junction temperature.
- 2) Repetitive rating; pulse width limited by max. junction temperature.
- 3) Pd is based on max. junction temperature, using junction-case thermal resistance.
- 4) The value of R_{θJA} is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with T_a=25 °C.
- 5) V_{DD}=100 V, V_{GS}=10 V, L=80 mH, starting T_j=25 °C.

Electrical Characteristics Diagrams

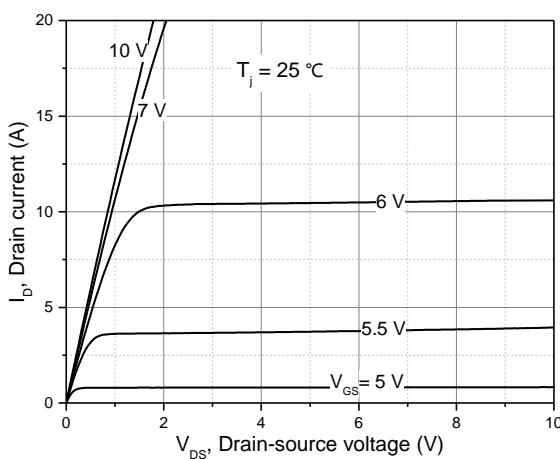


Figure 1. Typ. output characteristics

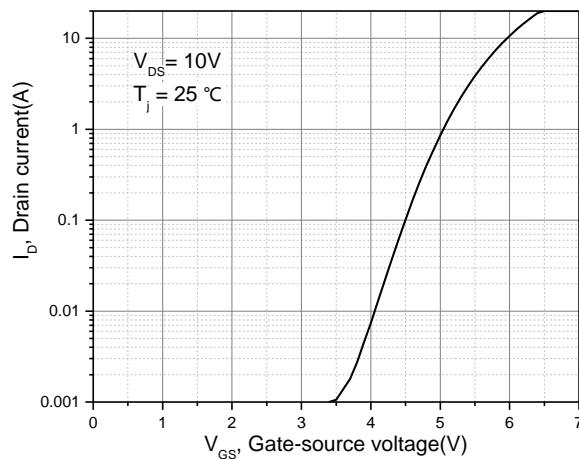


Figure 2. Typ. transfer characteristics

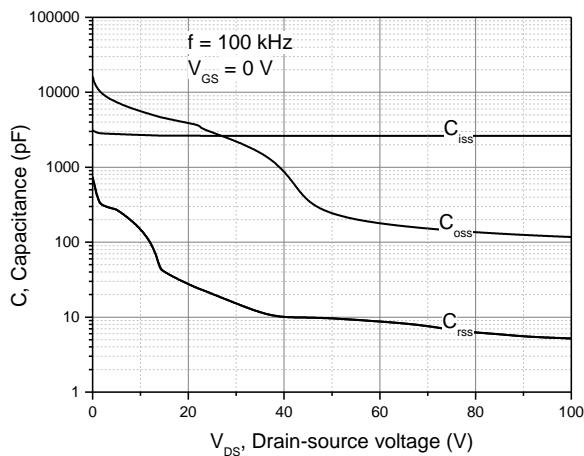


Figure 3. Typ. capacitances

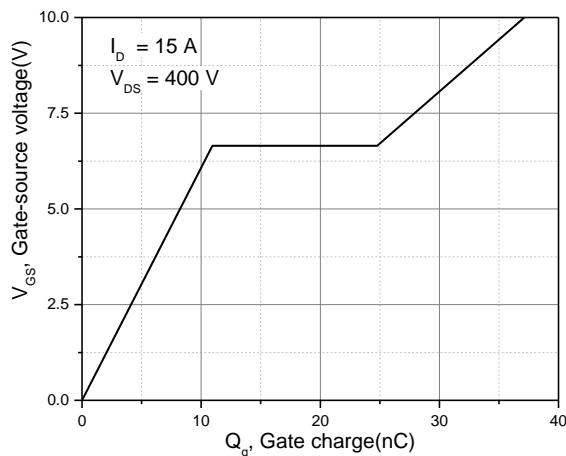


Figure 4. Typ. gate charge

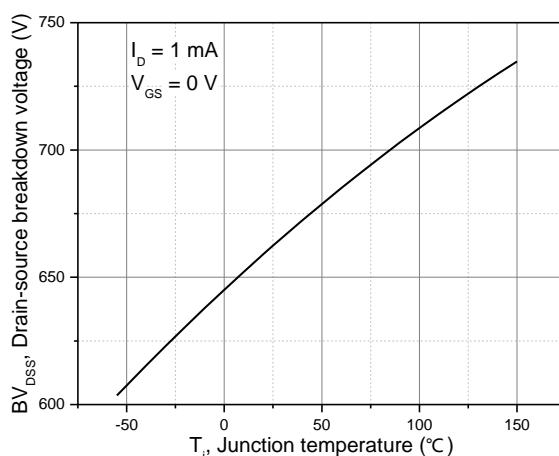


Figure 5. Drain-source breakdown voltage

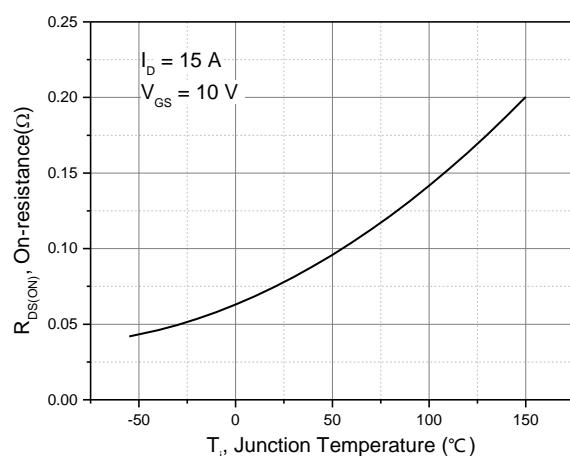
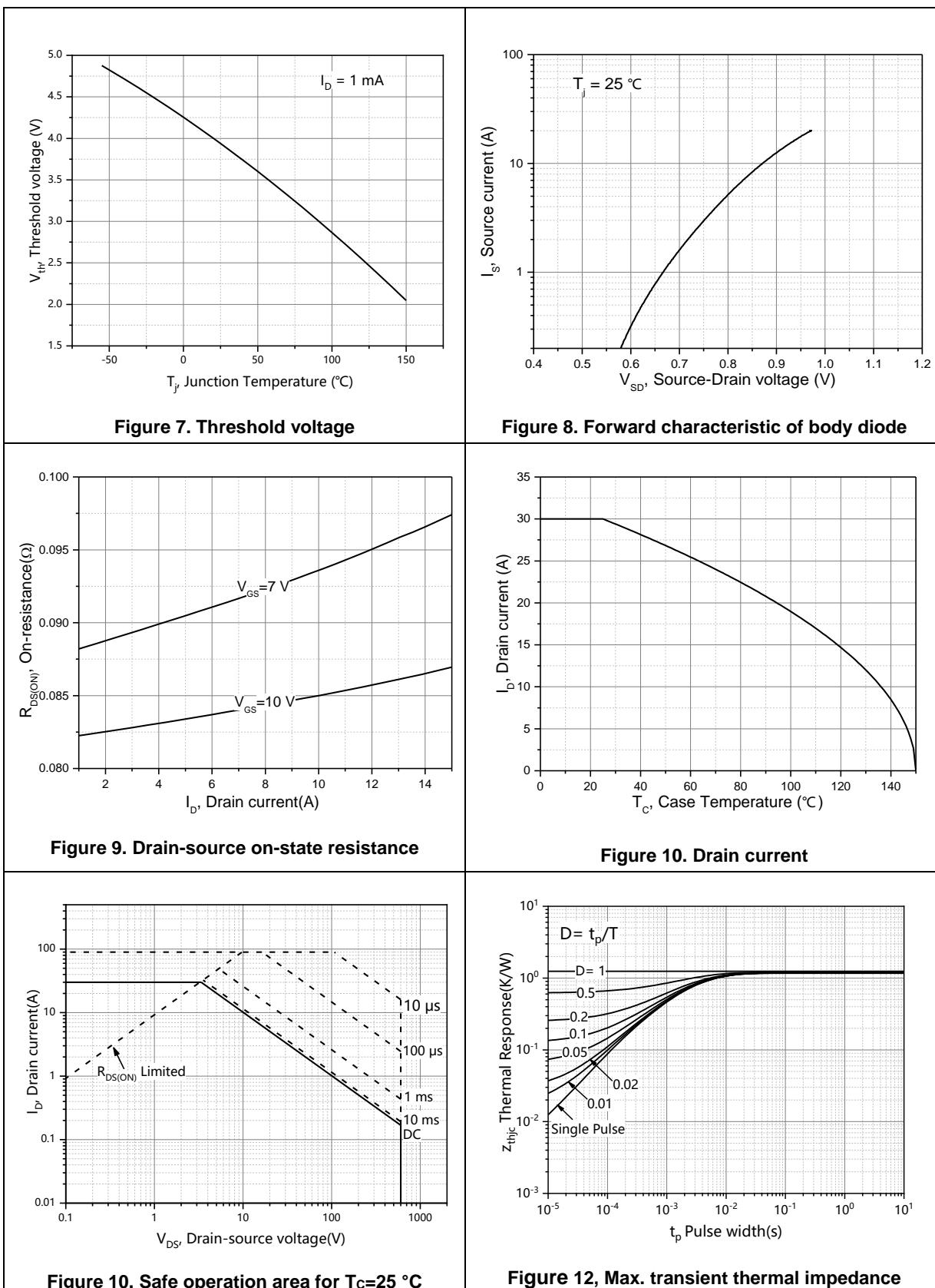


Figure 6. Drain-source on-state resistance



Test circuits and waveforms

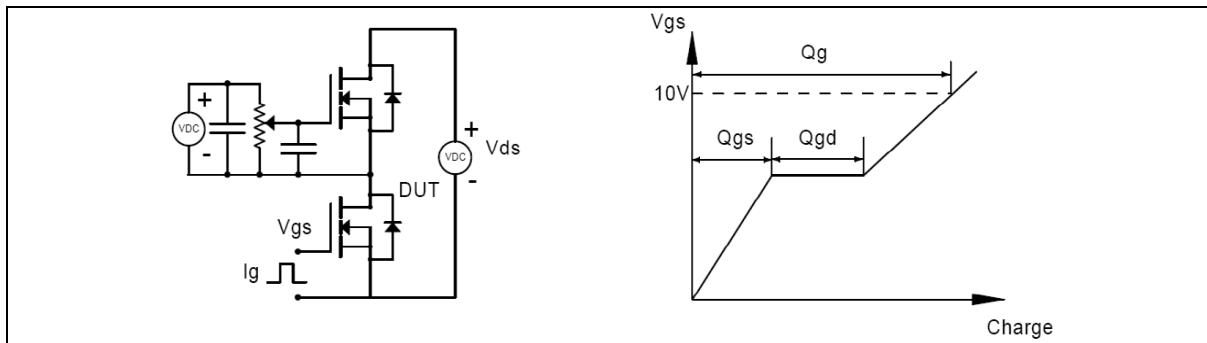


Figure 1. Gate charge test circuit & waveform

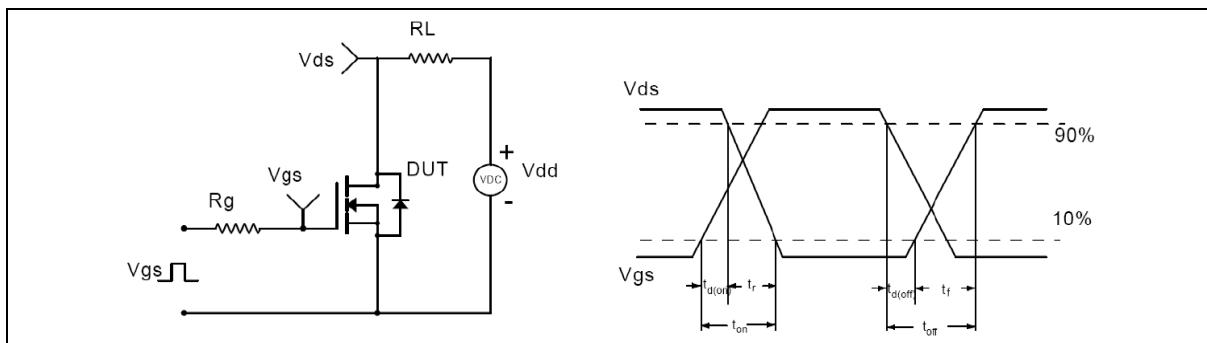


Figure 2. Switching time test circuit & waveforms



Figure 3. Unclamped inductive switching (UIS) test circuit & waveforms

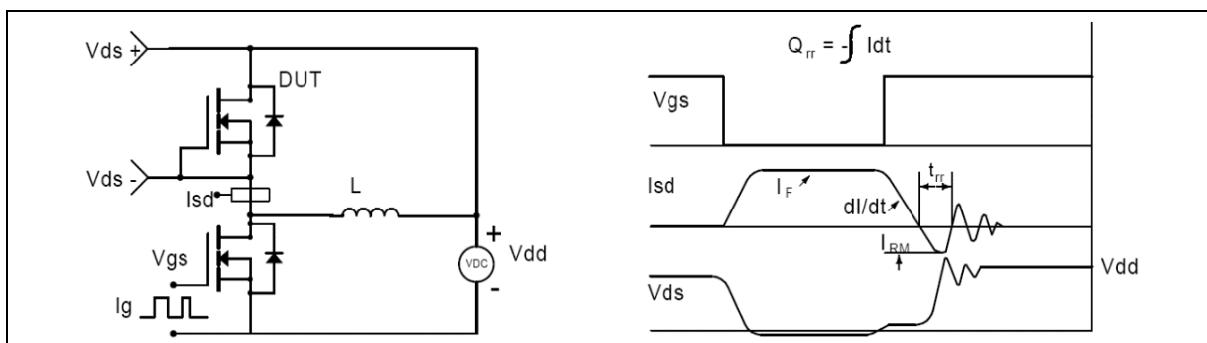
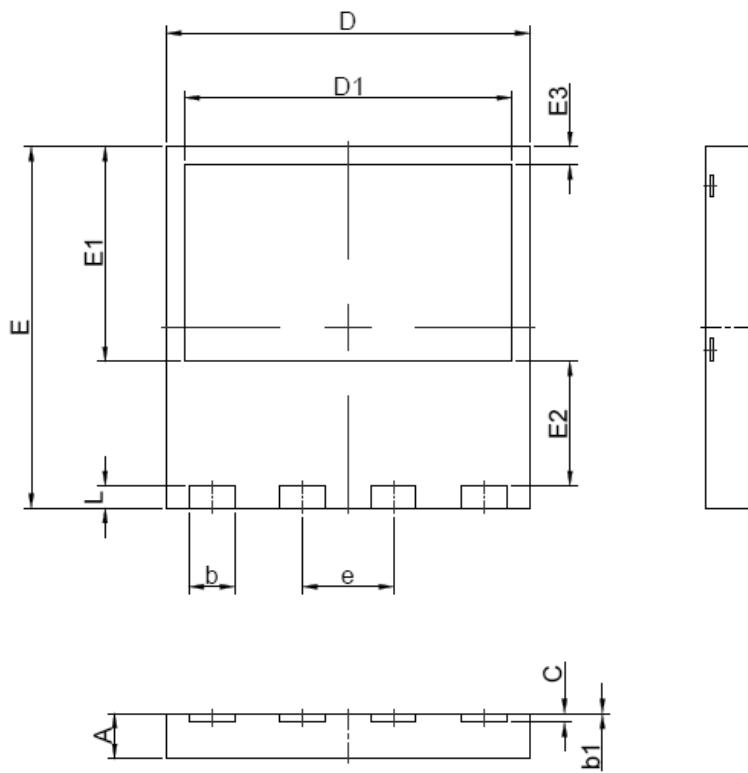


Figure 4. Diode reverse recovery test circuit & waveforms

Package Information



Symbol	mm		
	Min	Nom	Max
A	0.90	1.00	1.10
b	0.90	1.00	1.10
b1	0.00	0.02	0.05
C	0.2 REF		
D	7.90	8.00	8.10
D1	7.10	7.20	7.30
E	7.90	8.00	8.10
E1	4.65	4.75	4.85
E2	2.65	2.75	2.85
E3	0.3	0.4	0.5
e	2.0 BSC		
L	0.4	0.5	0.6

Version 1: PDFN8*8-L package outline dimension

Ordering Information

Package Type	Units/Reel	Reels/Inner Box	Units/Inner Box	Inner Boxes/Carton Box	Units/Carton Box
PDFN8*8-L	2500	1	2500	10	25000

Product Information

Product	Package	Pb Free	RoHS	Halogen Free
OSG60R108JZF	PDFN8*8	yes	yes	yes

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